

Notice of References Cited	Application/Control No. 10/543,140		Applicant(s)/Patent Under Reexamination KINOSHITA ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0043154 A1	03-2004	Ichikawa et al.	427/355
*	B	US-2004/0058817 A1	03-2004	Ueno et al.	503/201
*	C	US-2004/0115556 A1	06-2004	Nakamura, Hideyuki	430/200
*	D	US-2005/0099479 A1	05-2005	Mizutani et al.	347/103
*	E	US-6,951,027 B2	09-2005	Kikuchi et al.	720/718
*	F	US-2005/0233173 A1	10-2005	Odamura et al.	428/800
*	G	US-2006/0073312 A1	04-2006	Hattori, Ryoji	428/195.1
*	H	US-7,371,708 B2	05-2008	Arai et al.	503/201
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.